



Advance Analysis Capability

No.	Instrument / Technique	Technique (Abbrev)	Leadtime (working days)
1	Light Microscopy	LM	1
2	Scanning Electron Microscopy (SEM)/ Energy Dispersive X-ray (EDX)	SEM/EDX	2
3	Field Emission Scanning Electron Microscopy (FESEM)/Energy Dispersive X-ray (EDX)	FESEM/EDX	3
4	X-Section Sample Preparation	X-S	4
5	X-Section Sample Preparation for Complex Sample	X-SCS	5
6	Sputter Coating (per run) < 3 samples per run	SC	1
7	Scanning Acoustic Microscopy	C-SAM	3
8	Decapsulation – Chemical, CNC Milling, Laser Milling	Decap	5
9	Thermal Analysis FITR, TGA, DSC, TMA, GC-MS - 1 spot	TA	5
10	Fourier Transforms Infra-Red Spectroscopy (Micro-FTIR) - 1 spot	MicroFTIR	3
11	XRF/EDXRF/WDXRF – Plating Thickness, RoHS, Chemical Composition	XRF	5
12	Solderability Test – Wet Balance	WB	3
13	2D X-Ray Images	2DX-Ray	2
14	3D X-Ray Imaging	3DX-Ray	NA
15	Emission Microscopy – IC Fault Isolation	EM	6
16	NIR Emission Microscopy – IC Fault Isolation	NIREM	6
17	Laser Scanning Microscopy – IC Fault Isolation OBIRCH or TIVA	LSM	6
18	Backside Sample Preparation - CNC Milling	BSP	3
19	Auger Electron Spectroscopy (AES) / X-Ray Photoelectron Spectroscopy (XPS)	AES/XPS	5
20	Auger Electron Spectroscopy (AES) Depth Profile1 profile, depth<50nm	AES-DP	5
21	Auger Electron Spectroscopy (AES) Element Map Max 3 maps	AES-EM	5
22	X-ray Photoelectron Spectroscopy (XPS) Depth Profile1 profile, depth<50nm	XPS-DP	5
23	Focused Ion Beam (FIB) in general	FIB-G	5
24	Focused Ion Beam (FIB) Precision X-Section Sample Preparation	FIB-X-S	10
25	Transmission Electron Microscopy (TEM) Analysis with Regular Sample Preparation	TEM-RS	10
26	Transmission Electron Microscopy (TEM) Analysis with Precision Sample Preparation	TEM-PX-S	10
27	Atomic Force Microscopy (AFM) 1 spot Imaging	AFM	5
28	Optical Surface Profilometry - 1 profile Imaging	LSP	4
29	General Failure Analysis	GFA	POA
30	Reliability Test services – Temp Shock, Humidity, Salt Spay, EM, SIR, MFG	RTS	POA
31	Physical Property Test Services – Tensile, Pull, Peeling, Bend, Hardness.	PTS	POA
32	Consultant and Generating the report	CGR	3

- Remark : 1) Image Transforms (M) Sdn. Bhd reserves legal right to revise the analytical prices with respond to market situation.
 2) We strongly advise customers to further detail discussion on their specific sample analysis and result requirement.
 3) Lead-time for technical analysis on light-blue highlighted must be discussed separately as we have established strategic alliance relationship with our oversea partner's lab
 4) Customers will arrange their samples to our laboratory and freight charges shall be borne by customers..
 5) Customer will also bear the responsibility to arrange samples to Image Transforms (M) Sdn. Bhd with above address.